

**Search Notes**

Application/Control No.

10/768,416

Examiner

David T. Fidei

Applicant(s)/Patent under  
Reexamination

SHENKAR ET AL.

Art Unit

3728

**SEARCHED**

Class	Subclass	Date	Examiner
206	219 221 222	3/2/2006	DTF
215	DIG. 8	3/2/2006	DTF

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR